

Authors	Energy Range (eV)	Technique	Temperature (K) RT unless specified	Sample				Data Presentation	Remarks Am
				Film	X-tal	Bulk	Prep		
NSW76	1.27-7.51	Ref1		x				R,n,k	plotted R corrected for window reflectivity

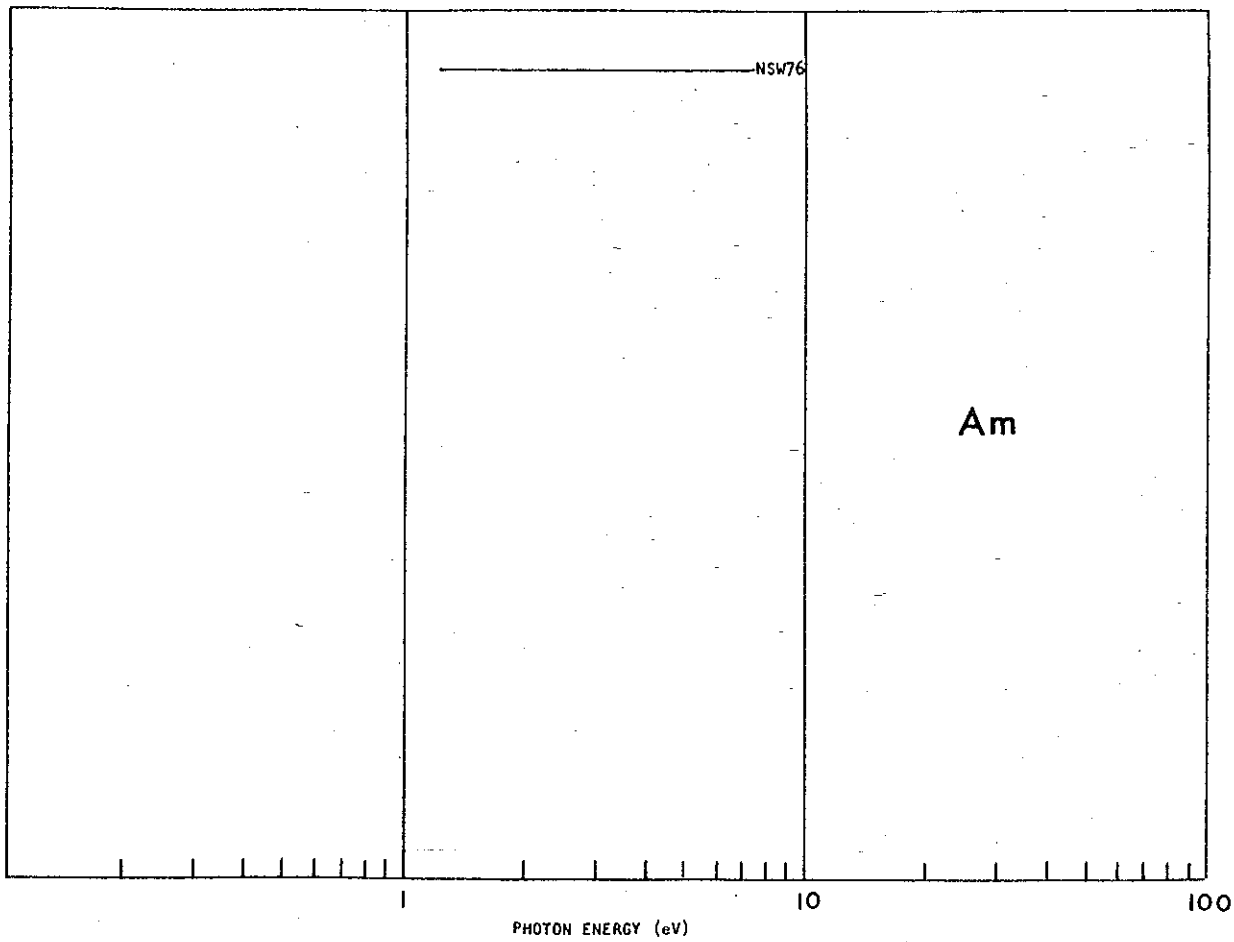


Fig. 102 Survey of available data on Am.

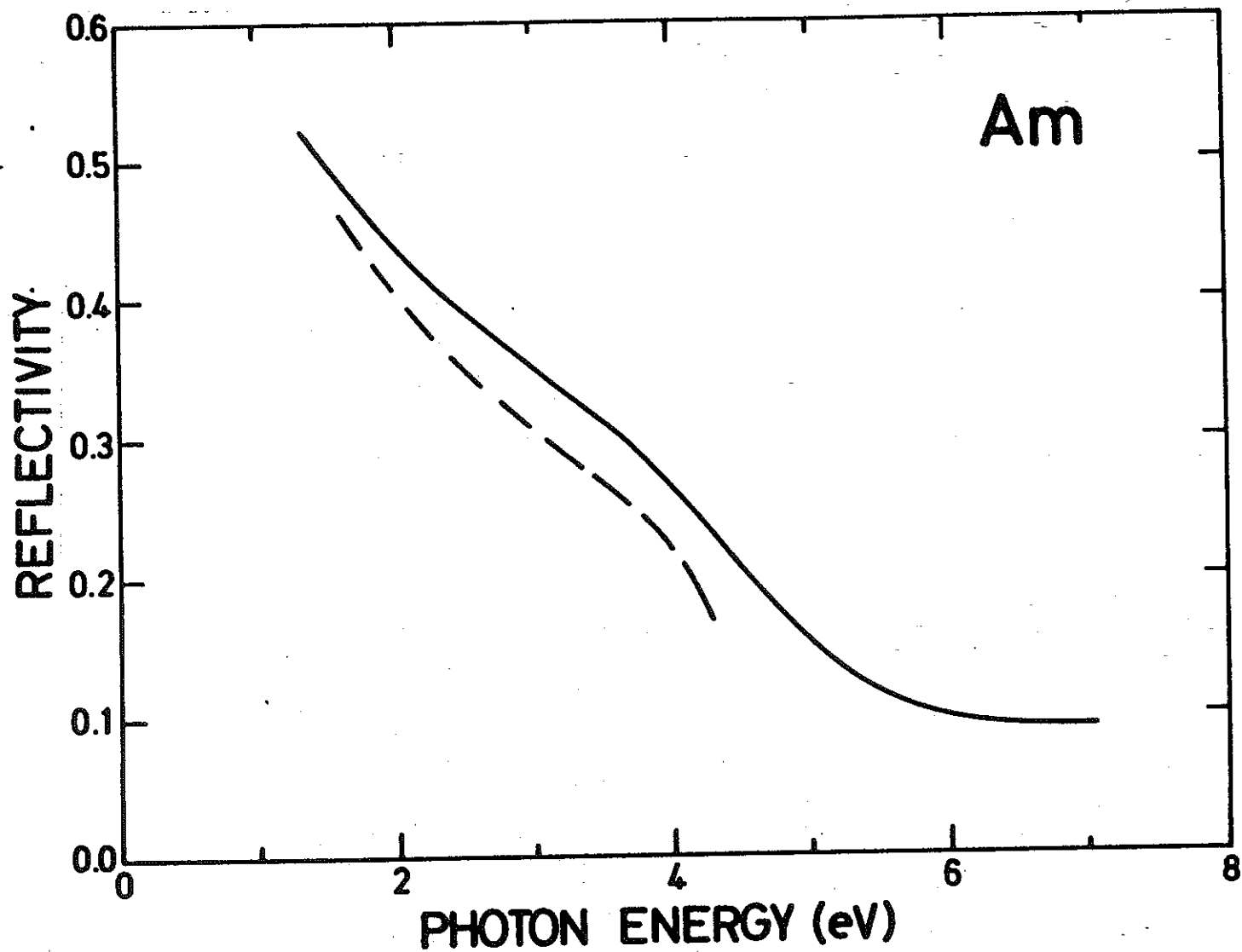


Fig. 103 Reflectivity for Am. Polycrystalline results by NSW76 using films evaporated onto Al₂O₃ (—) and SiO₂ (---).